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CERTIFICATE OF MAILING

I hereby Čertify that this correspondence is being deposited on May 18, 2005 with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to: Mail Stop Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Name of Person Mailing Paper: Aimee Harrison

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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No:

10/749,887

Filing Date:

December 31, 2003

Art Unit:

1756

Applicant:

Dixon et al.

Title:

METHOD AND SYSTEM TO COMPENSATE FOR LAMP

INTENSITY DIFFERENCES IN A PHOTOLITHOGRAPHIC

INSPECTION TOOL

Atty Docket:

CT-004

Mail Stop Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Applicant hereby submits the references listed on attached PTO-1449 and calls them to the attention of the Patent and Trademark Office for the above-referenced case. No admission is made that the cited art represents the prior art or that the cited art is the most material art. This application was filed after June 30, 2003, and therefore, no copies are enclosed of the U.S. Patents or Published applications cited as references herein.

I hereby certify that each item of information contained herein was cited for the first time in a communication in a counterpart application from a foreign patent office not more than three months prior to the filing of this Information Disclosure Statement. (37 C.F.R. §1.97(e)(1))

Further, I hereby certify that each item of information contained herein was cited in a communication from a foreign patent office in a counterpart application and that this communication was not received by any individual designated §1.56(c) more than thirty days prior to the filing of this Information Disclosure Statement. (37 C.F.R. §1.704(d))

The Examiner is urged to consider the cited references and to make an independent decision with respect to their materiality.

It is submitted that the cited references alone or with the other art of record does not disclose or render obvious that subject matter claimed in the present application.

Applicants do not believe that any fees are due in connection with this submission. However, if such extension is due or any other fees are necessary, the Commissioner may consider this to be a request for such and charge any necessary fees to deposit account 23-3000.

Respectfully submitted,

WOOD, HERRON & EVANS, LALP

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EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE			CLASS	SUBCLASS		FILING DATE IF APPROPRIATE
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not in conformance. Draw line through citation only if not in conformance <u>and</u> not considered. Include a copy of this form with next communication to applicant.